

Charge Collection Studies for HV-MAPS



Bundesministerium
für Bildung
und Forschung

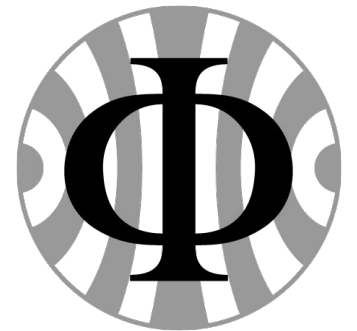
07.03.2024

DPG Spring Meeting Karlsruhe

Ruben Kolb

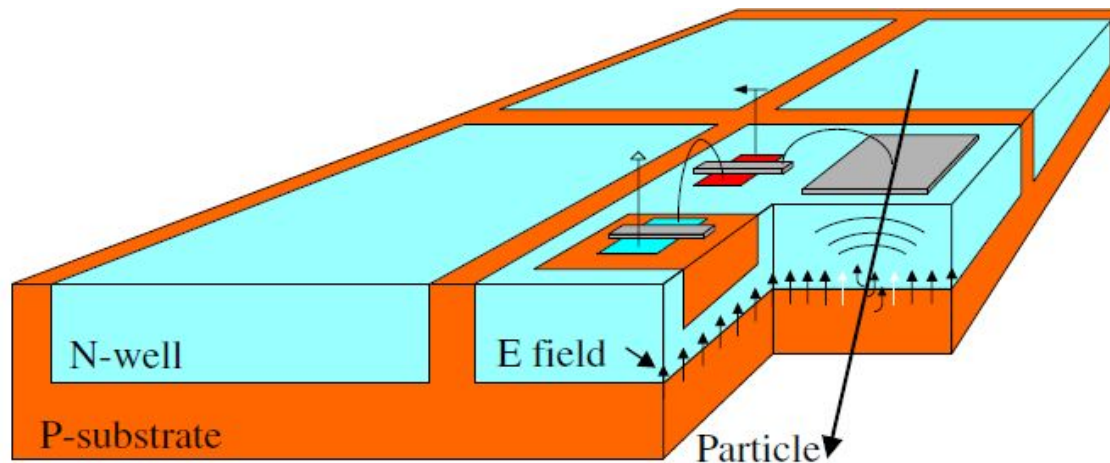
On Behalf of the HD HV-MAPS Collaboration

Physikalisches Institut Heidelberg



High Voltage - Monolithic Active Pixel Sensors (HV-MAPS)

- Monolithic: Readout and active volume on same chip



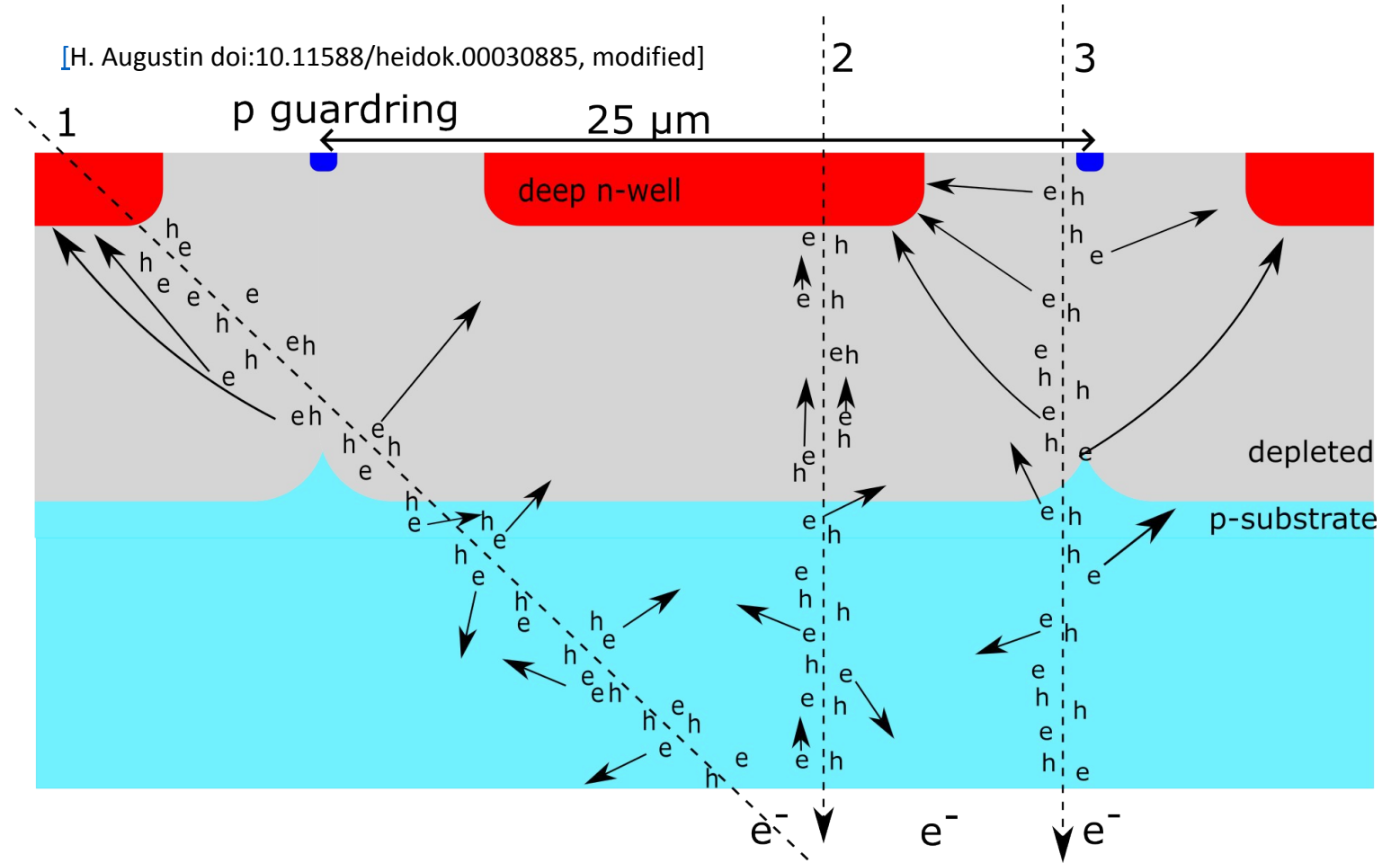
[I.Peric, P. Fischer et al., NIM A 582 (2007) 876]

Characteristics:

- Diode realised as deep n-well in p-substrate reversely biased up to -140 V
- $w \propto \sqrt{\rho U}$
- Fast charge collection via drift in depleted volume

Charge Deposition and Collection in HV-MAPS

[H. Augustin doi:10.11588/heidok.00030885, modified]



- Fast charge in depleted volume collected via drift
- Diffusion in non depleted volume

Time [ns]	Gaussian spread σ [μm]
500	62 ± 2.4
750	75 ± 3
1000	87 ± 3

→ How large is the contribution from diffusion?

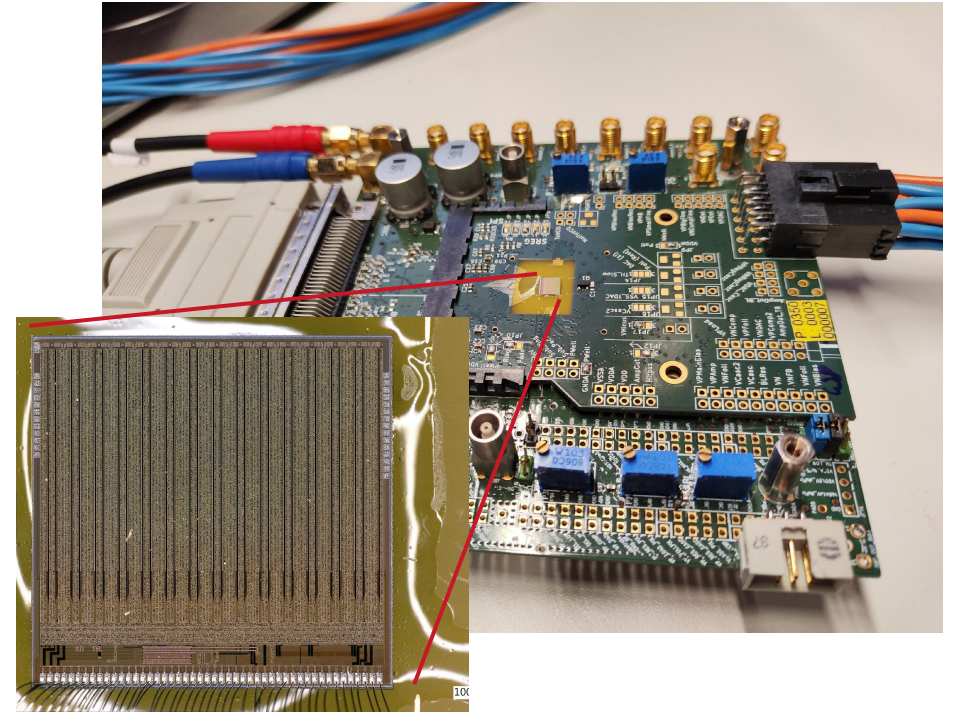
→ Main observables:
ToT, cluster size

$$\text{Fick's law: } \frac{dQ}{dx}(\vec{x}, t) = \frac{1}{8(\pi Dt)^{\frac{3}{2}}} \int Q_0(\vec{x}') e^{-\frac{(\vec{x}-\vec{x}')^2}{4Dt}} d\vec{x}' \rightarrow \sigma = \sqrt{2Dt}$$

TelePix1 (Run2021 V2)

- Small scale ($5 \times 5 \text{ mm}^2$) R&D sensor
- In-pixel electronics contain amplifier and CMOS comparator
- Measurement Idea:
Compare observables at same HV & configuration for different thicknesses

→ Following results focus on:
 $d = 50 \mu\text{m}, 100 \mu\text{m}; \rho = 370 \Omega\text{cm}$

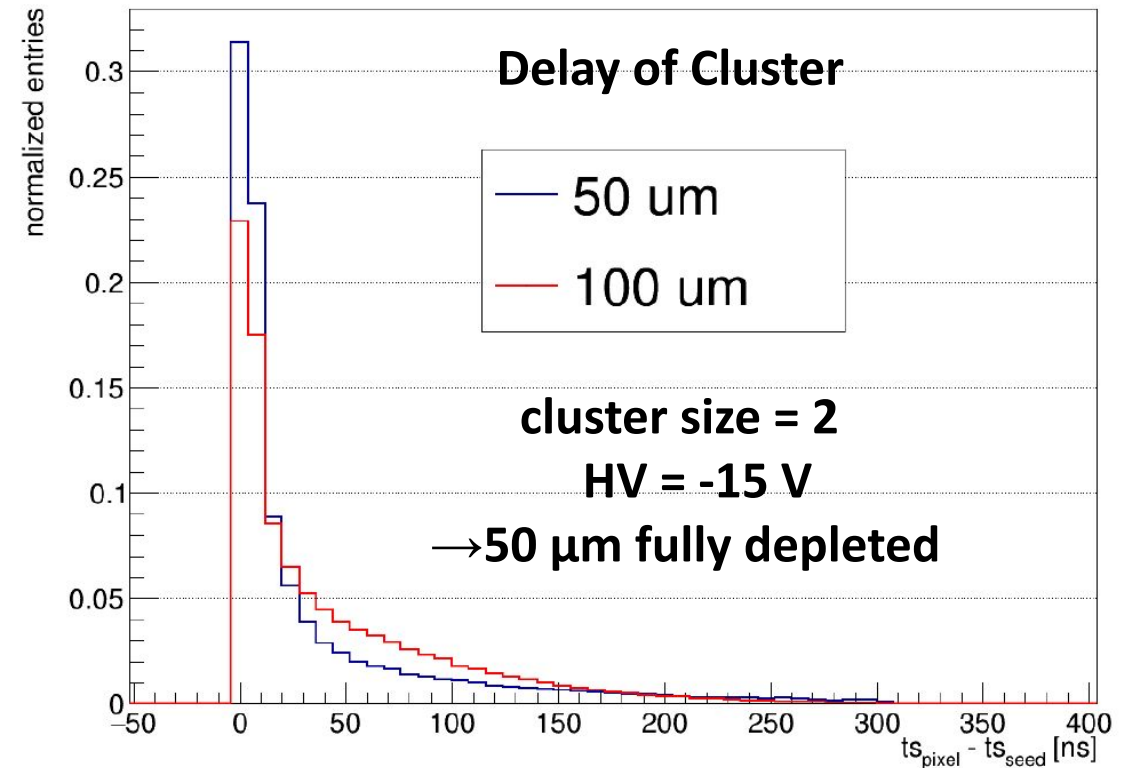
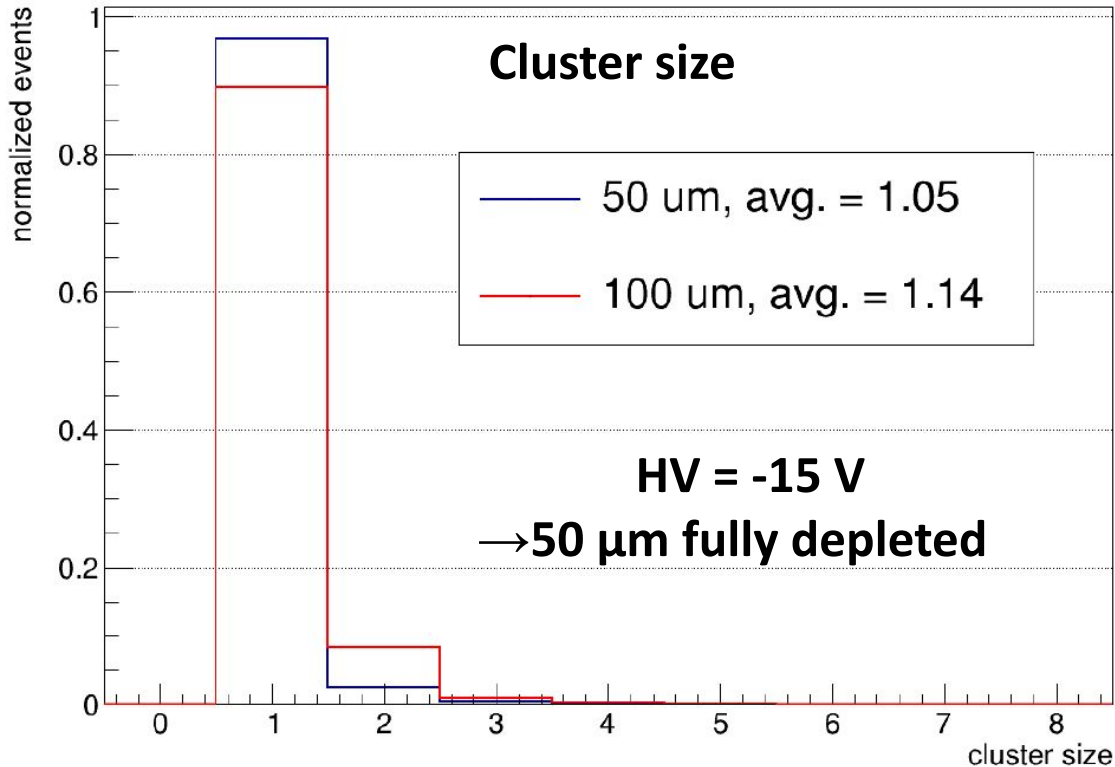


Substrate [Ωcm]	20, 370 , ~8000
Thickness [μm]	50, 100 , 300, 600
Matrix [Pixel]	29x124
Pixel size [μm^2]	165x25
Sensor size [mm^2]	5x5

Cluster Size Study @ DESY

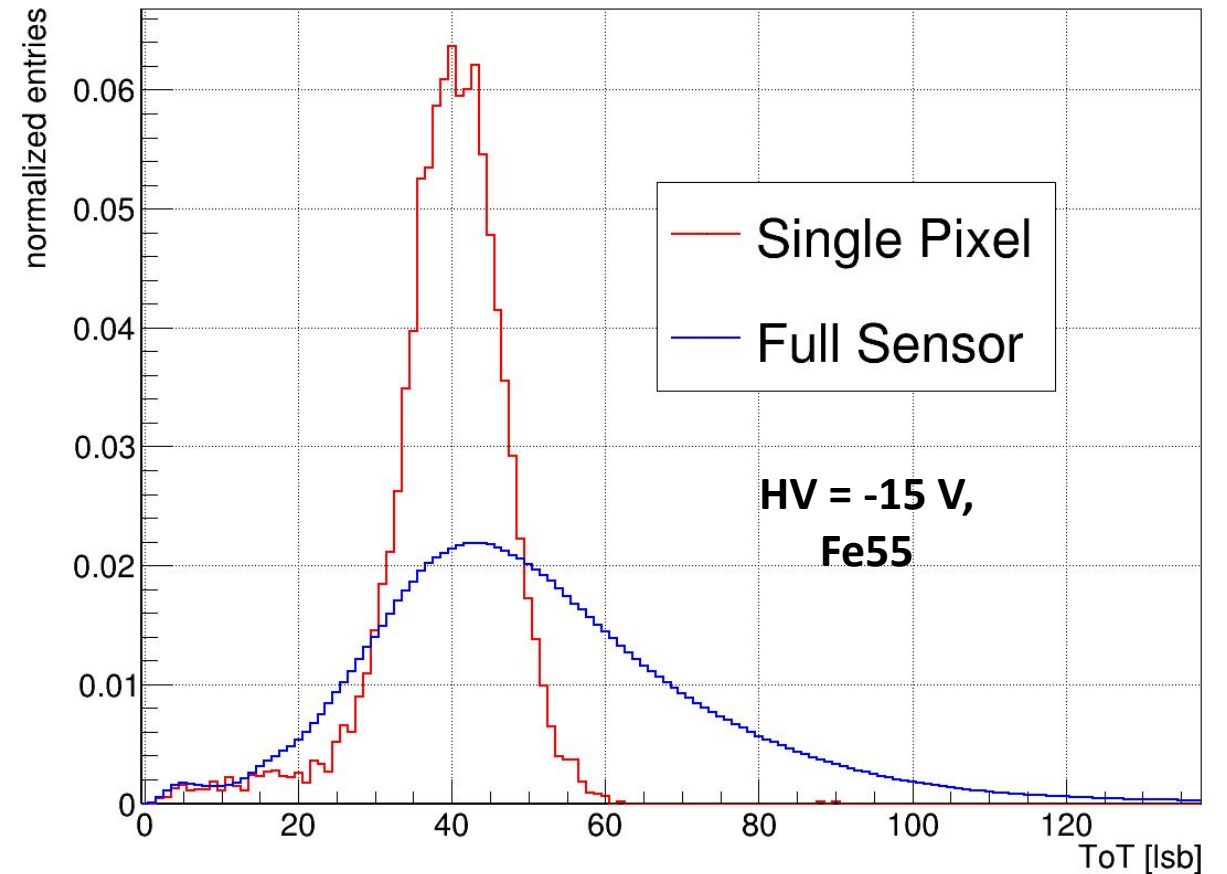
- Higher average cluster size with undepleted material
- Second Pixel in the cluster shows a more pronounced tail towards larger delays

→ Diffusion is a slow process



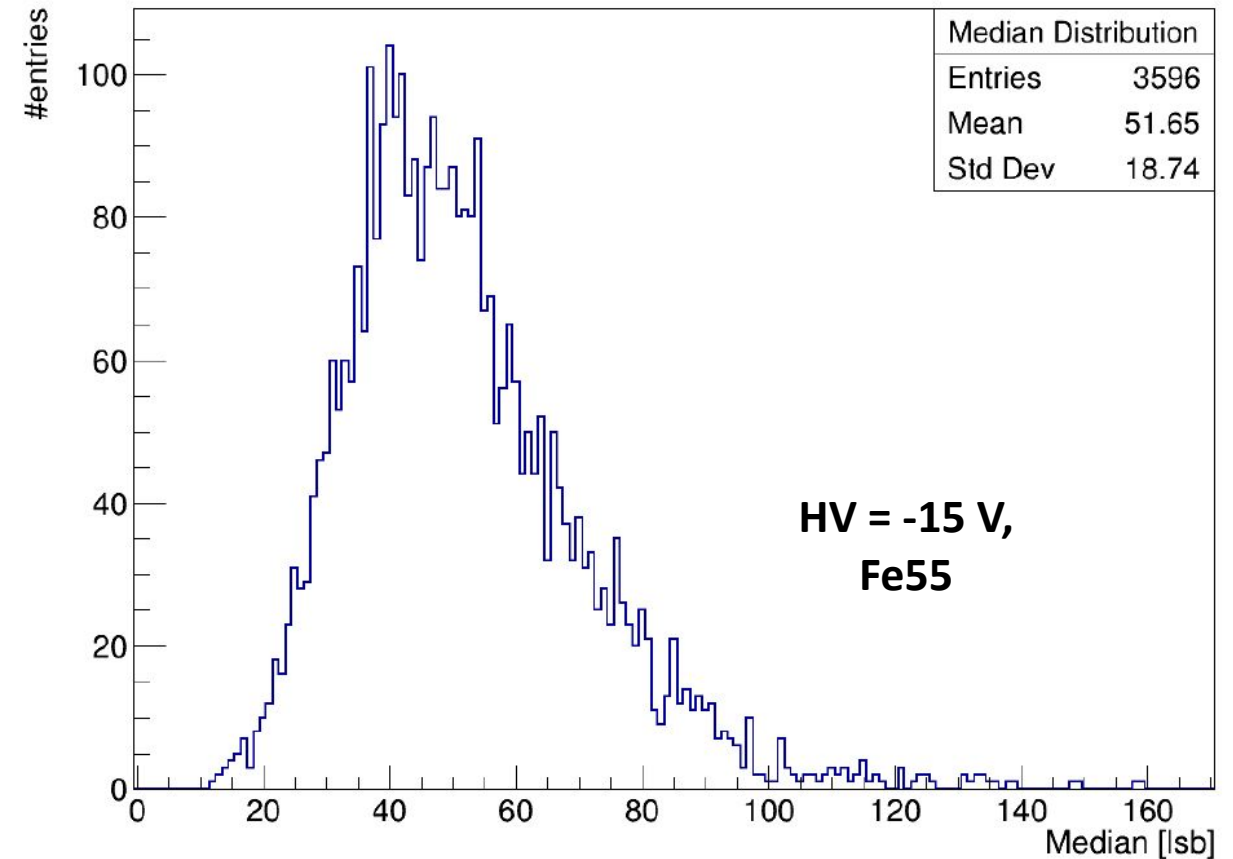
Pixel to Pixel ToT Variations

- Fe55: Monoenergetic x-ray source 5.9 keV → creates ~1634 e-h pairs
→ Similar pixel response expected
- Full sensor ToT has large FWHM



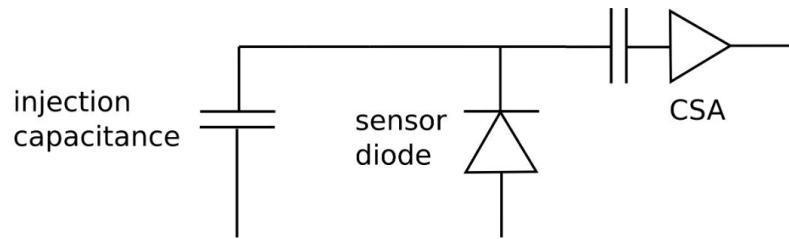
Pixel to Pixel ToT Variations

- Fe55: Monoenergetic x-ray source 5.9 keV → creates ~1634 e-h pairs
→ Similar pixel response expected
- Full sensor ToT has large FWHM
- Large variation in pixel median ToT for Fe55 source is observed
→ Variation from Chip to Chip
→ Calibration necessary

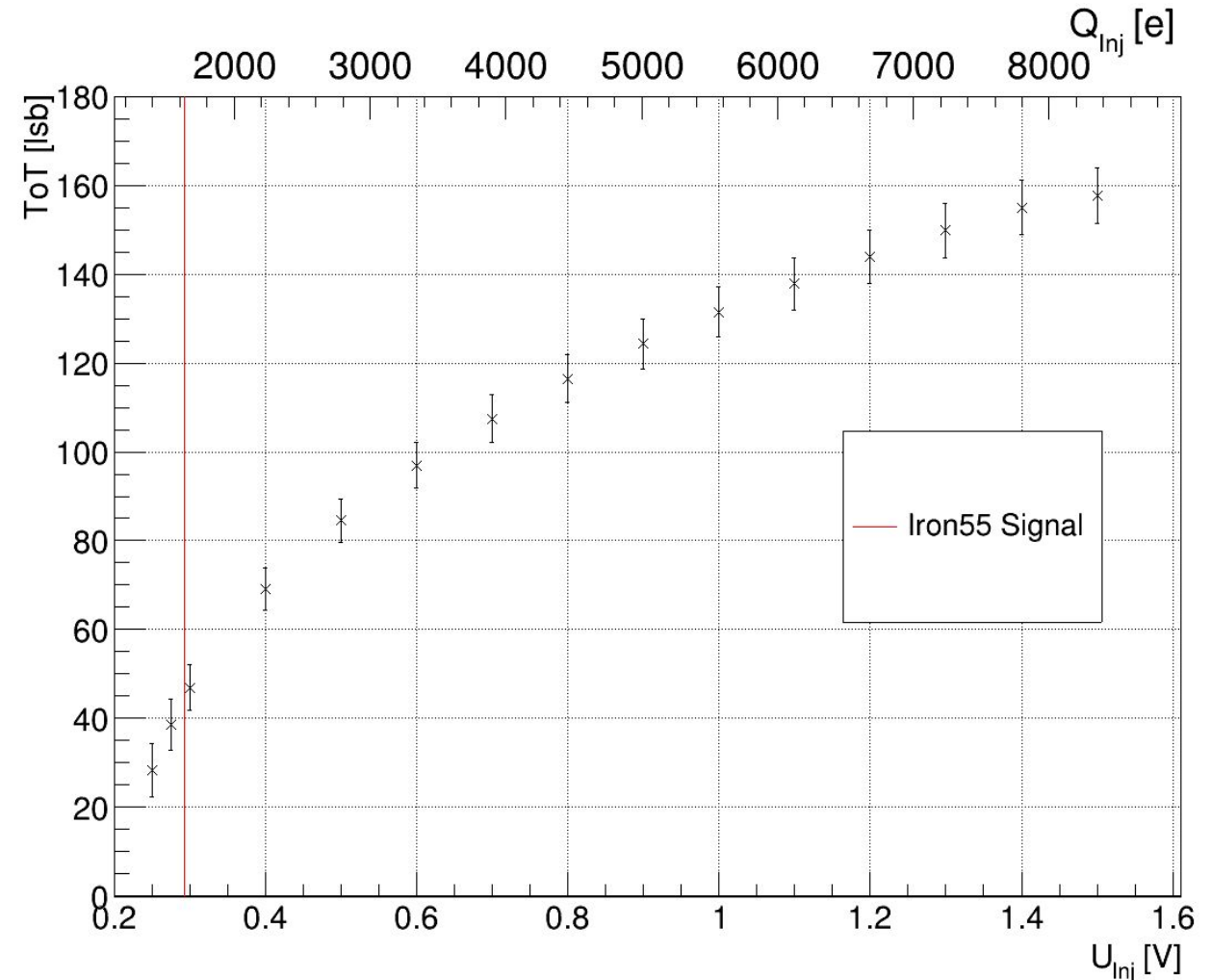


Amplifier Behavior

- Use of injection circuit: $Q_{\text{Inj}} = U_{\text{Inj}} \cdot C_{\text{Inj}}$
→ reliable, artificial signal source



- Injection study conducted with a **single** pixel
→ Logarithmic amplifier response (empirical)
- Non-linear calibration needed





Calibration Method

<https://doi.org/10.1088/1748-0221/16/03/P03008>

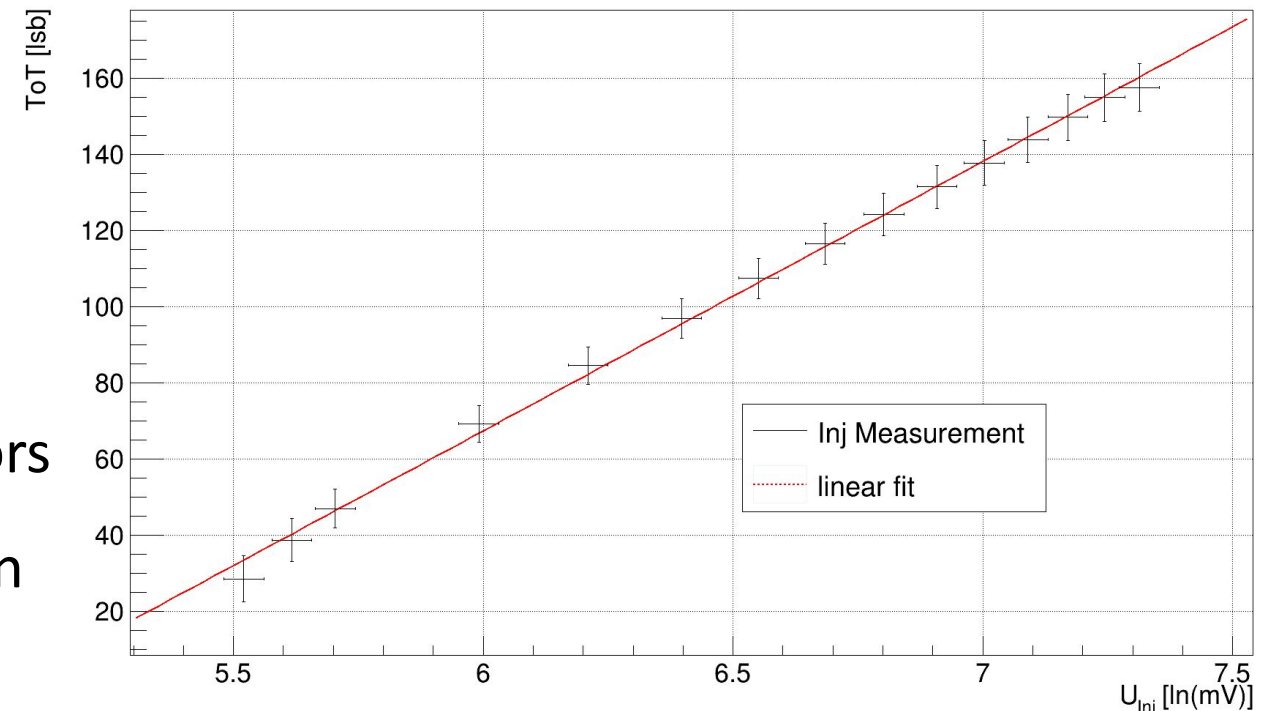
- Calibration in Corryvreckan → two new modules developed
- Analysis on per pixel level
- Exponential calibration function

$$C = 1634e^{-} * \exp(a * (ToT - ToT_{Fe}))$$

with a : fit gradient, C : collected charge

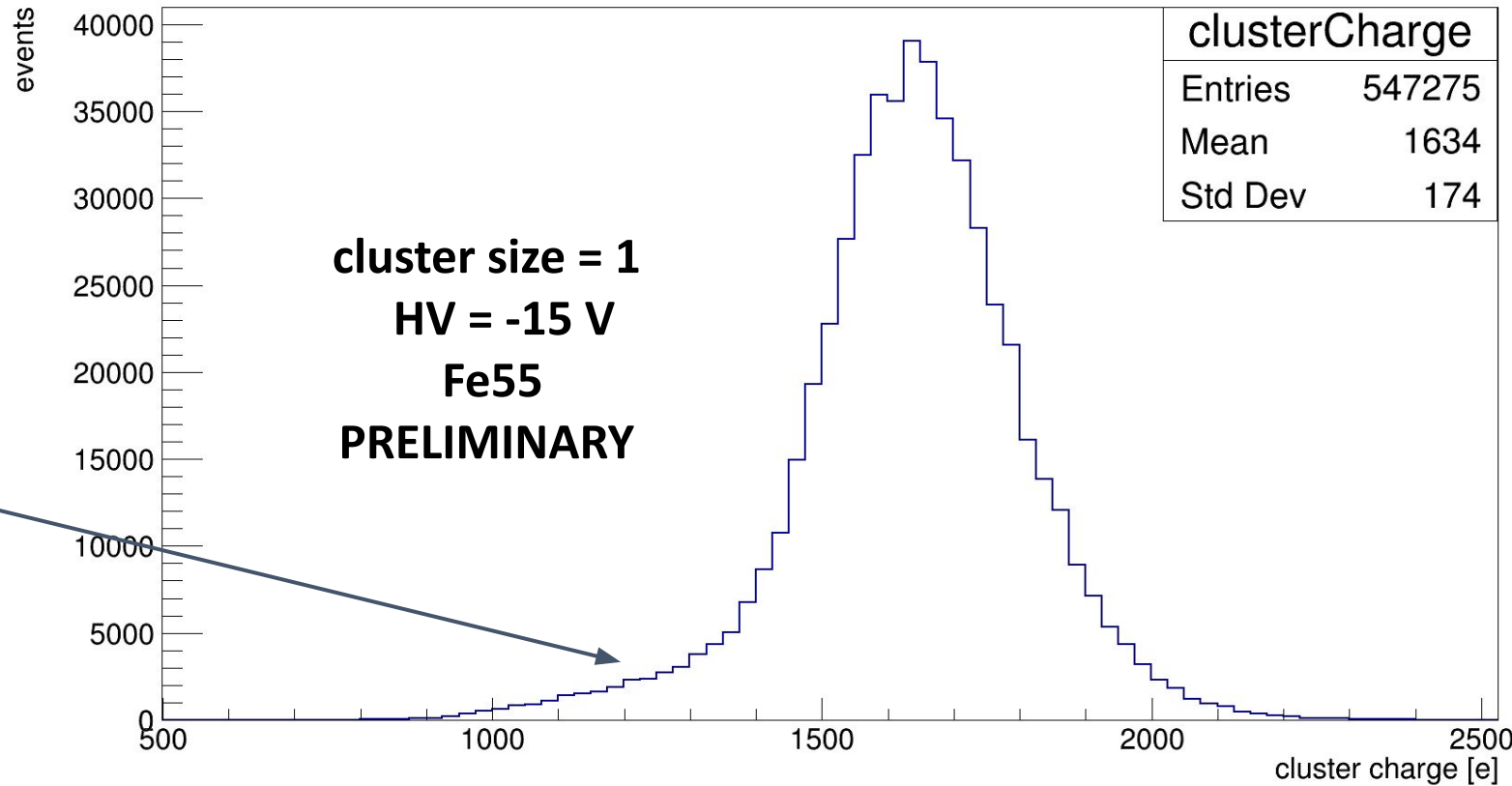
→ Achieves electron calibration for sensors

→ Allows for sensor to sensor comparison



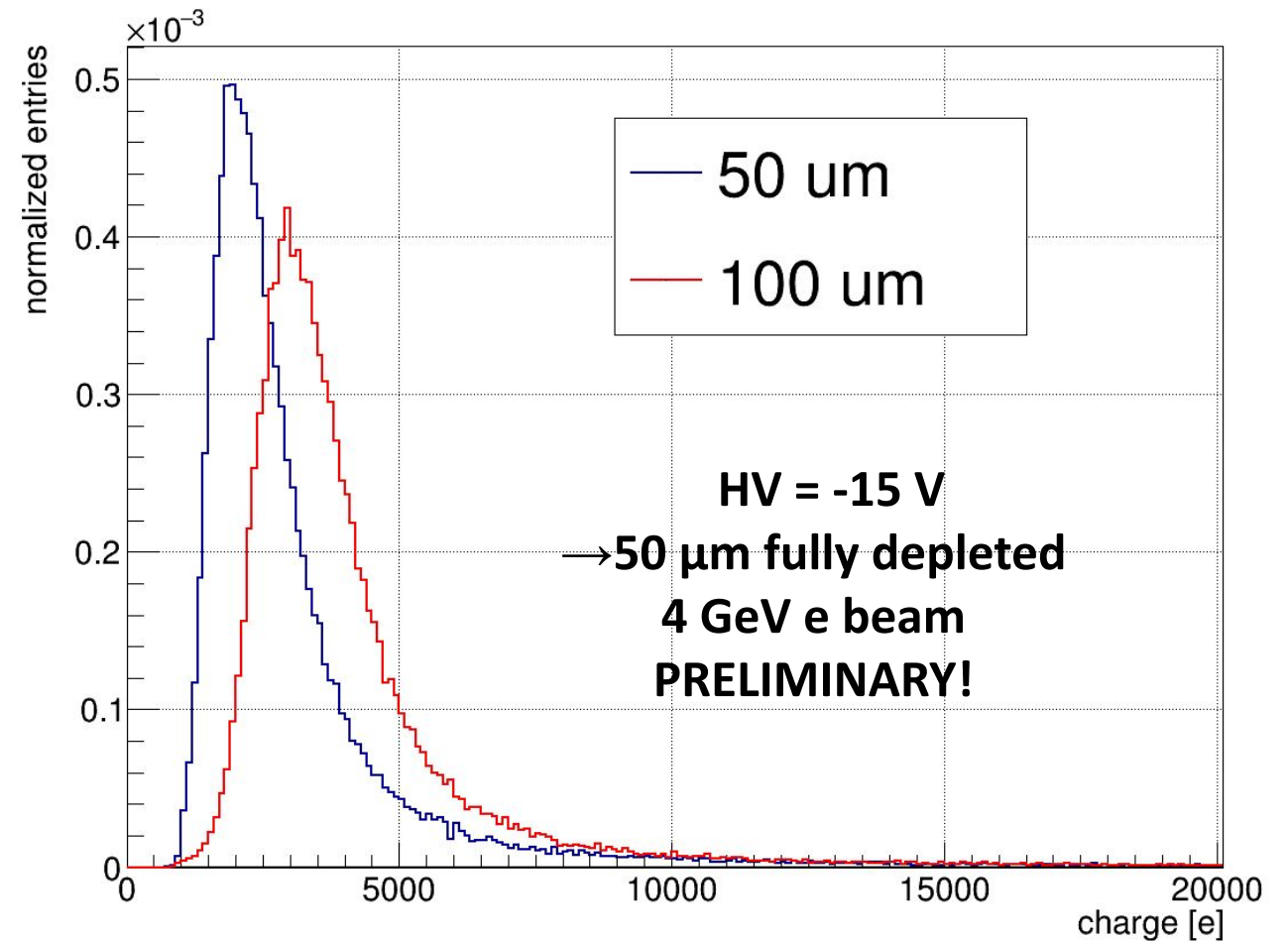
Calibration of Fe55

- Subset of 100 pixels
- Core of the distribution has Gaussian shape and mean 1634 electrons
- Tail towards small charge collections
→ charge sharing



Calibrated ToT Studies @ DESY

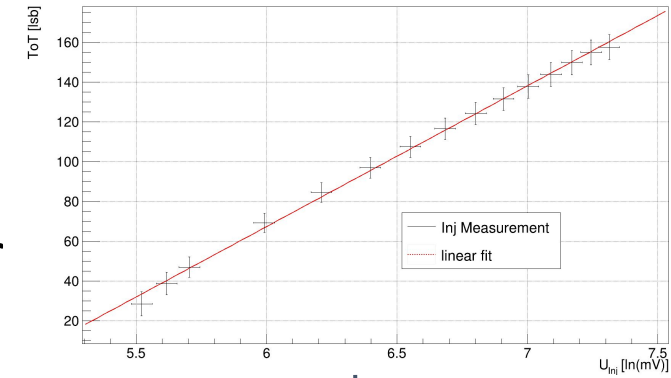
- Subset of 100 Pixels
- Clear separation of charge spectra
- Mean electron collection:
3349 e (50 μm) 4259 e (100 μm)
- Expectation from Berger-Seltzer for drift only: 3300 e



Conclusion & Outlook

Conclusion:

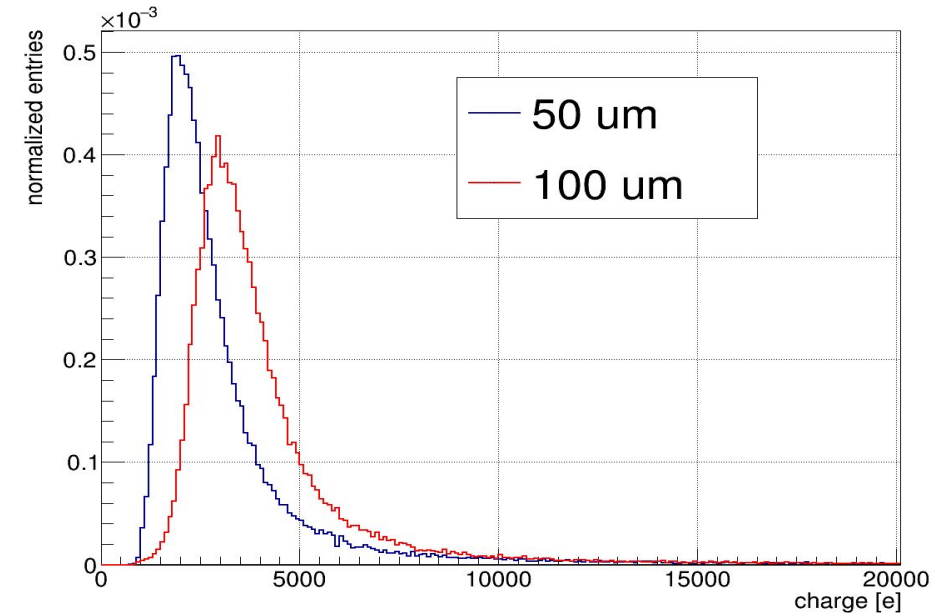
- Larger avg. cluster sizes with undepleted volume & delay of cluster
 - ~30% more collected charge in thicker sensor
- Significant contribution of diffusion to the signal is observed!



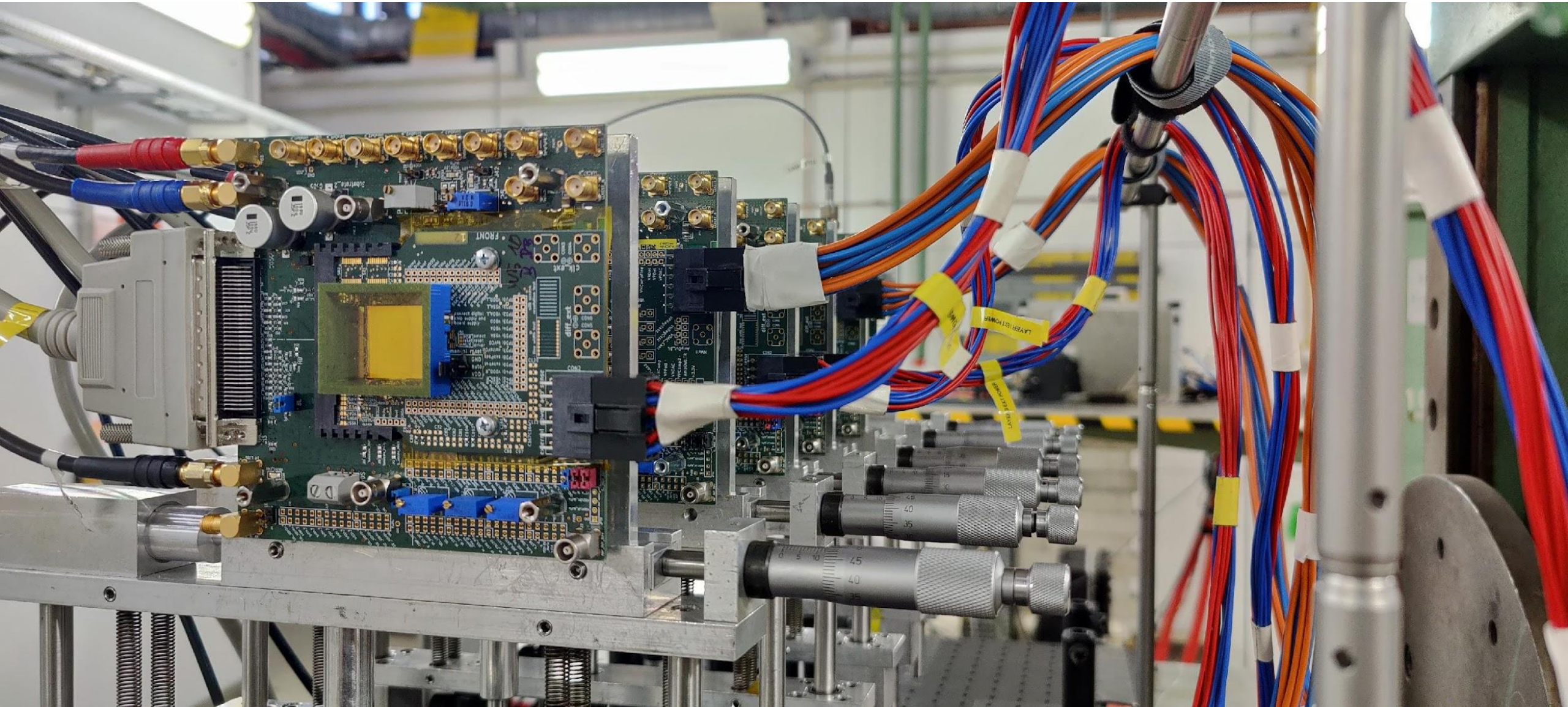
↓
 $1615e^- * \exp(a * (ToT - ToT_{Fe}))$

Outlook:

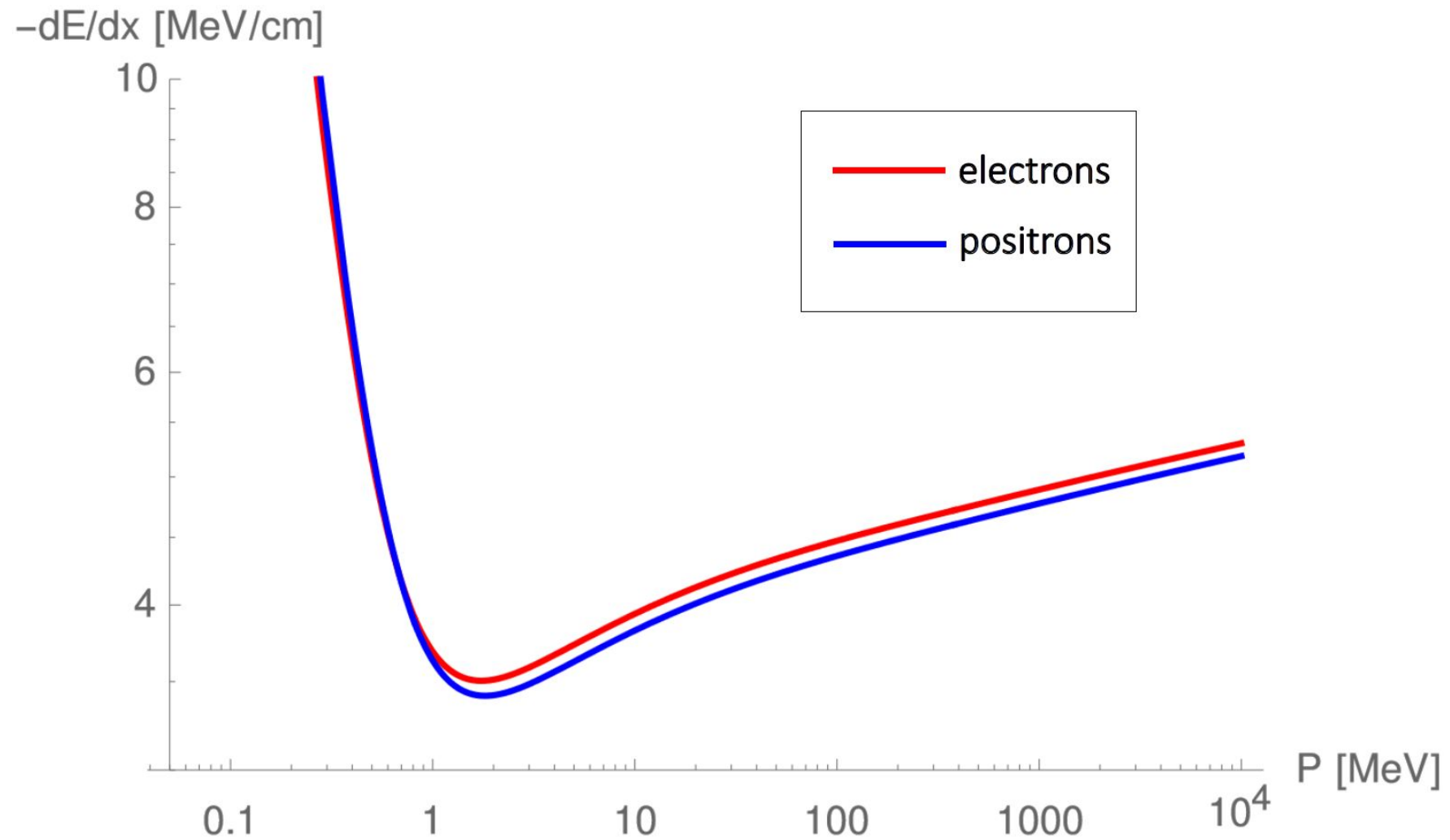
- Calibration for full sensor
- Allpix² Simulation



Questions?

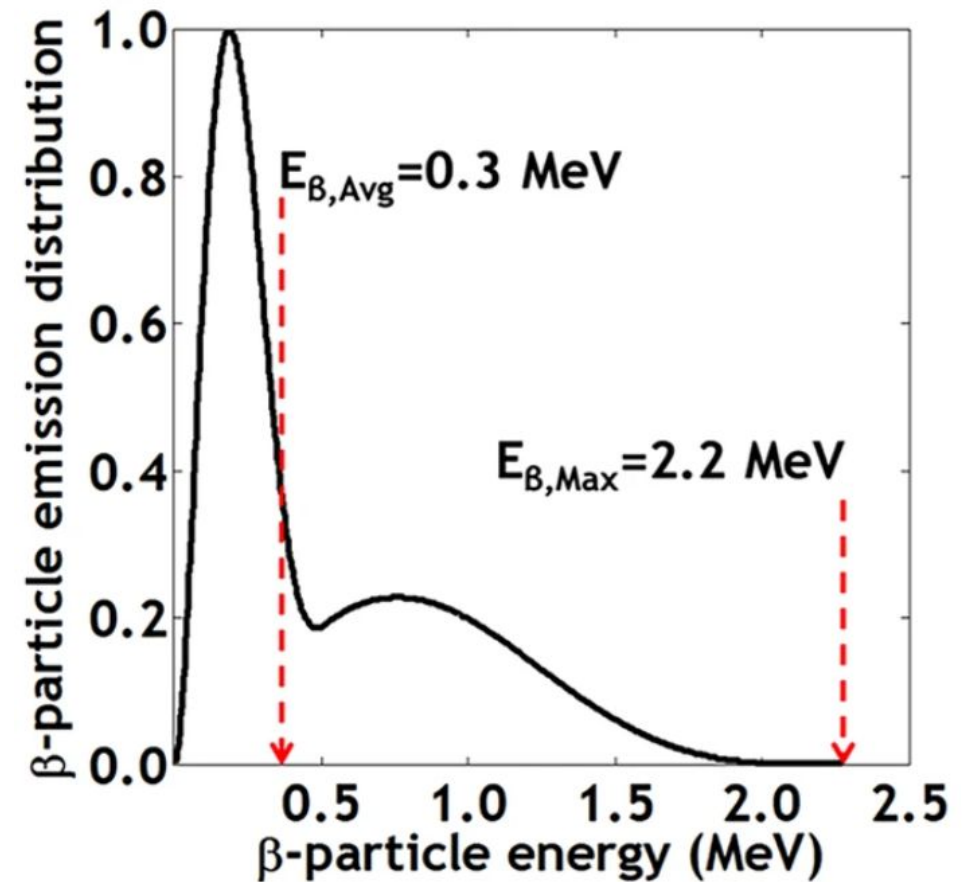


Berger-Seltzer



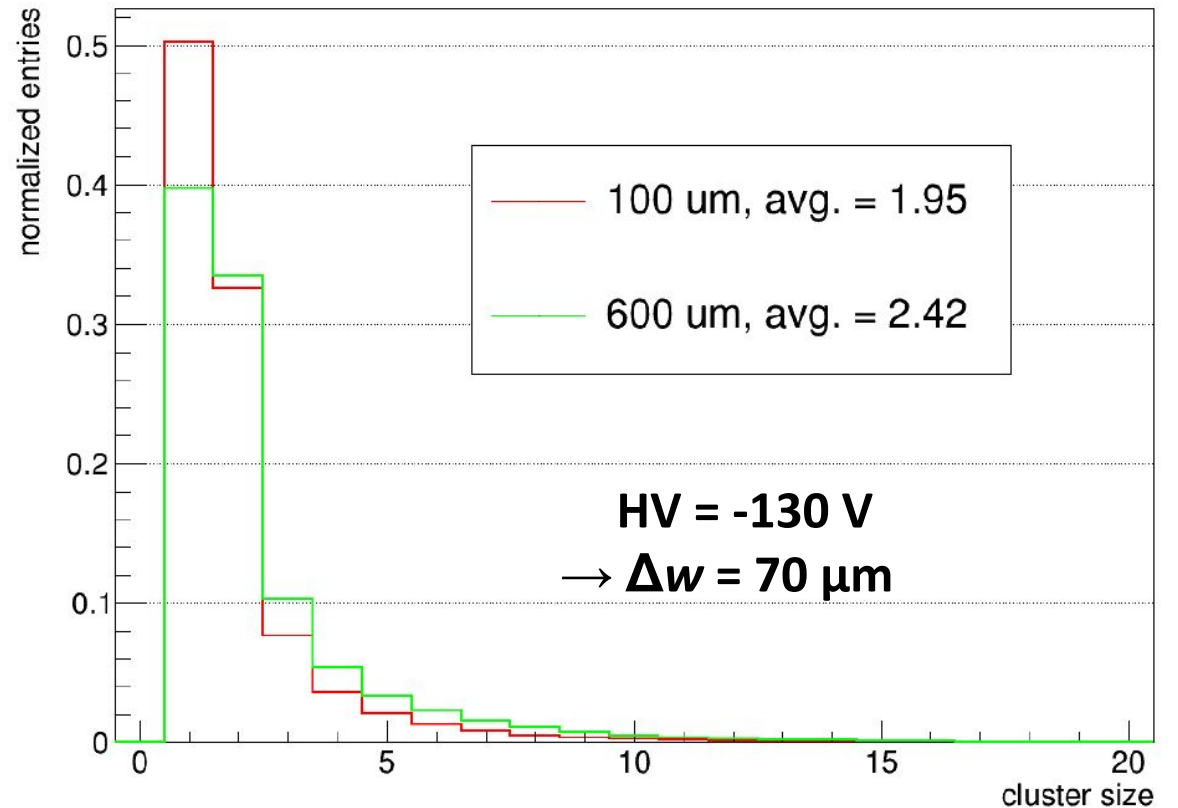
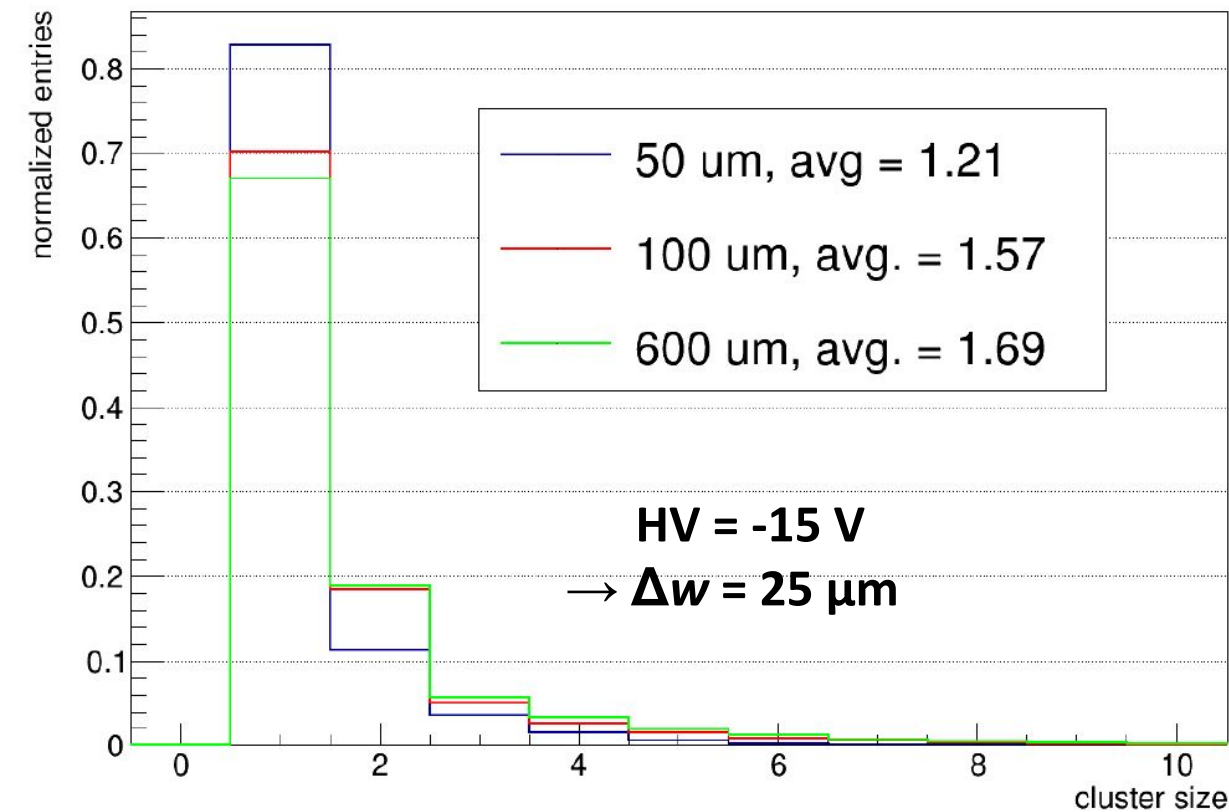
Sr90 calculated spectrum

- Low energy electrons do not reach the detector
→ Most probable energy: 0.8 MeV



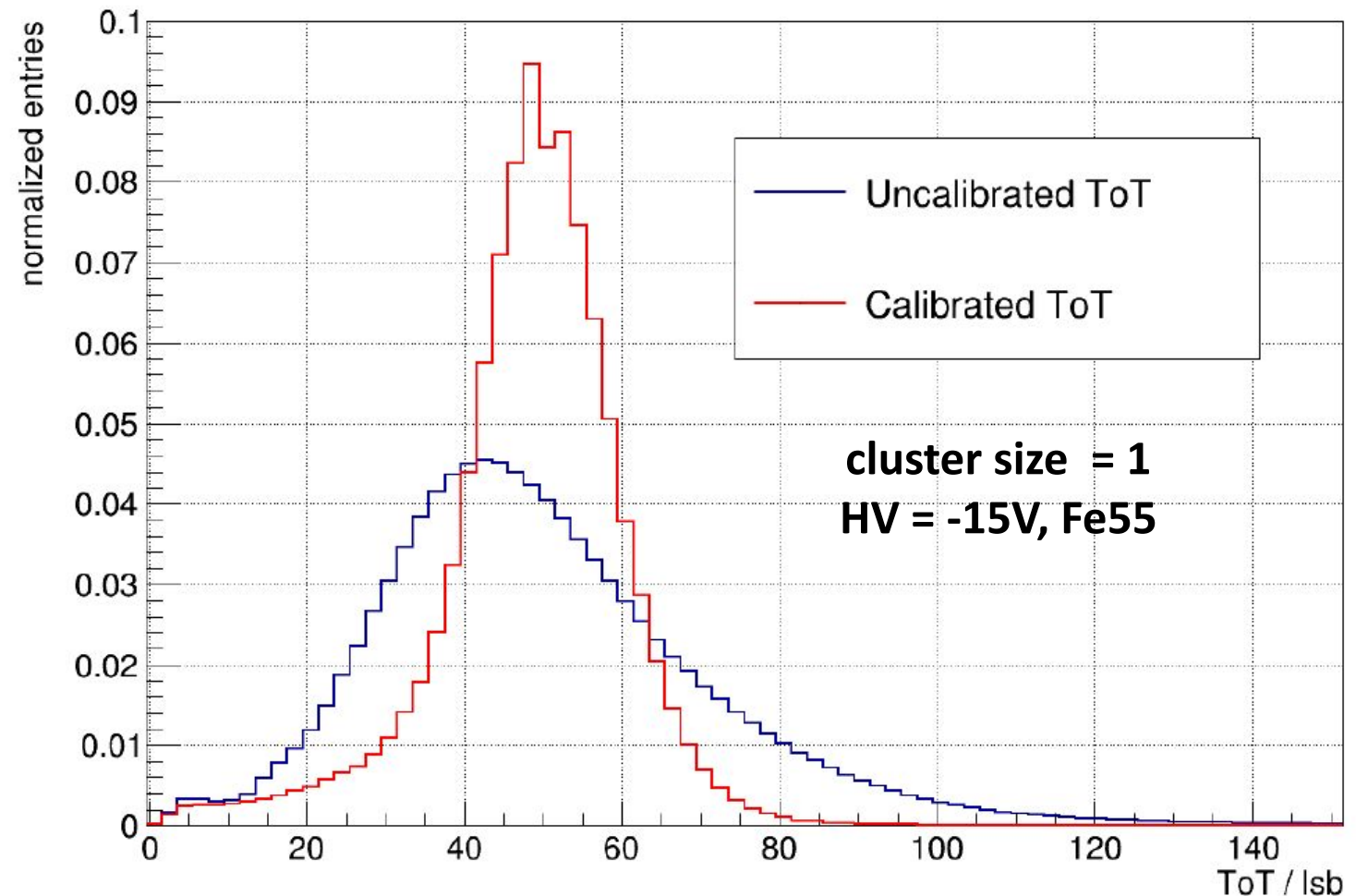
Cluster size studies Sr90

- Average cluster size increases with thickness
- For large diffusion volumina a constant offset in cluster size is observed



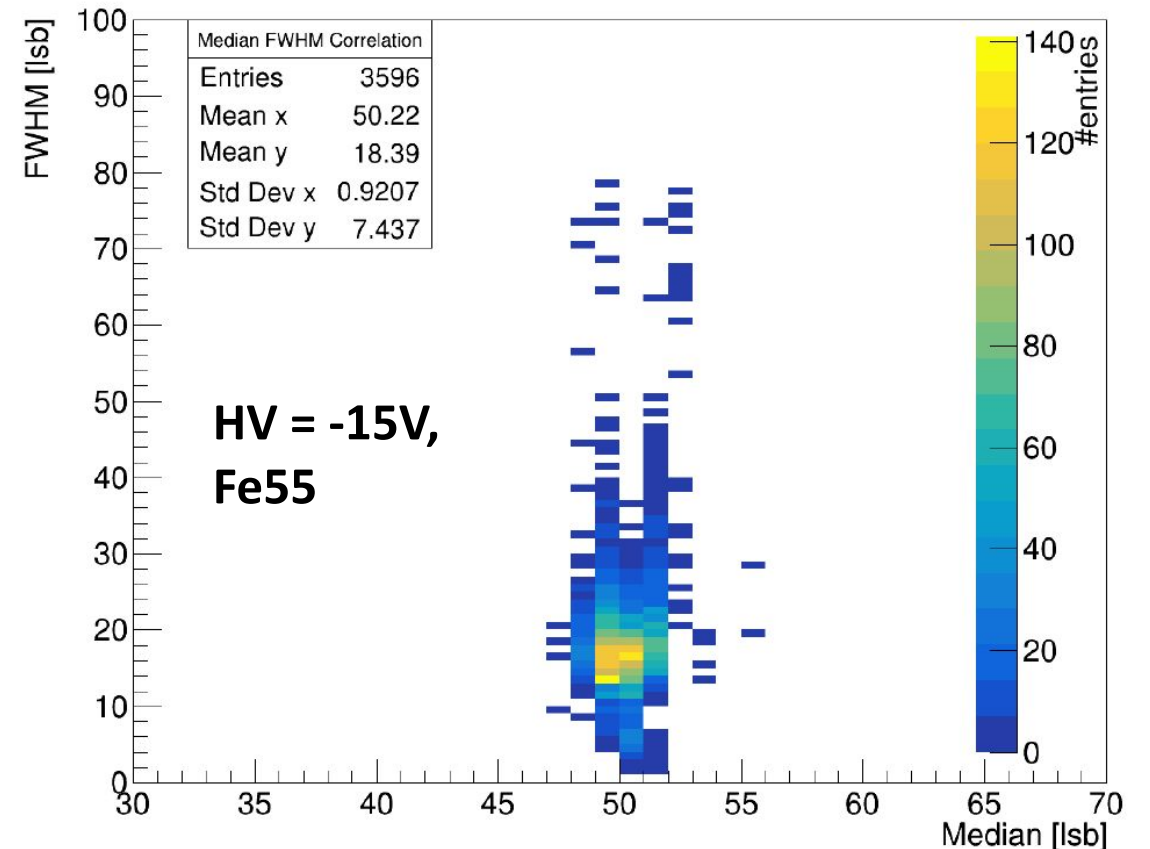
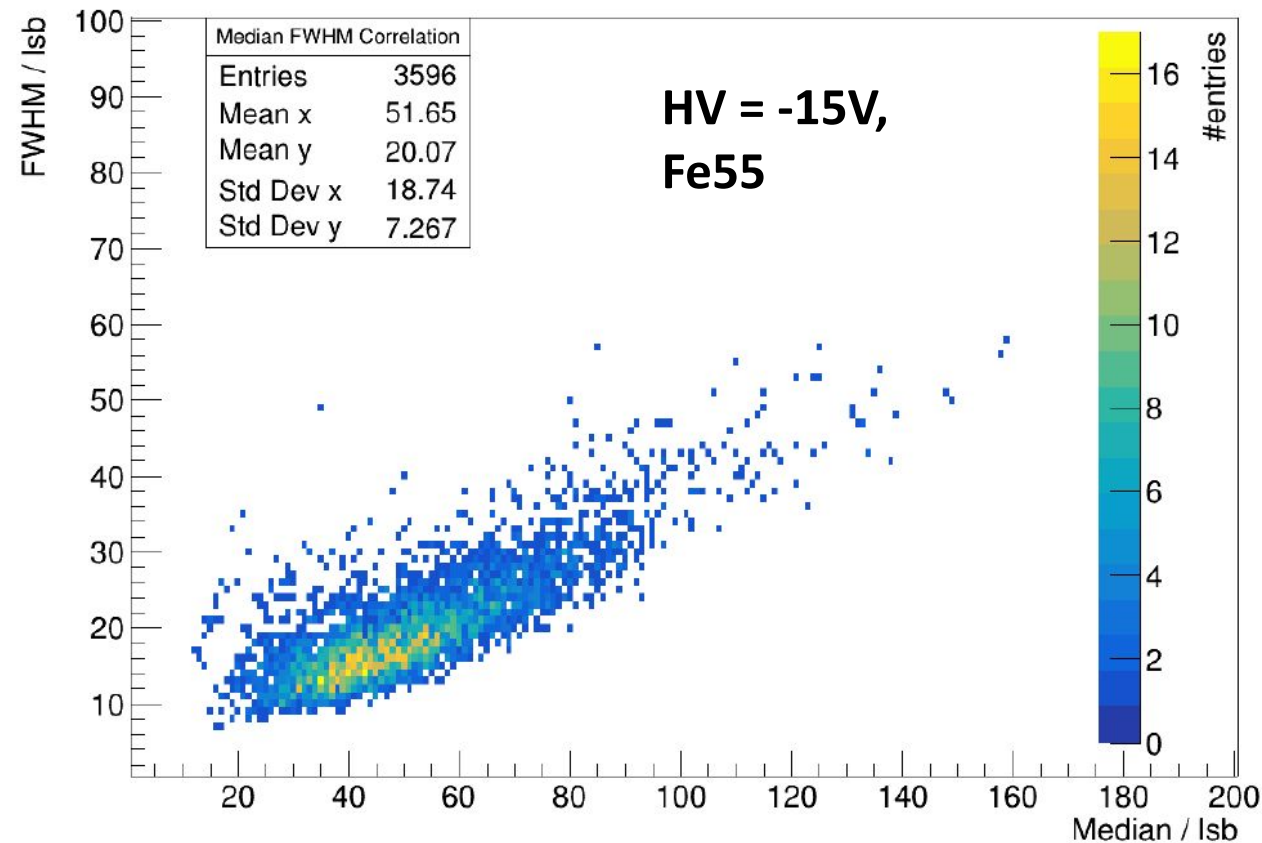
Quality Control of Calibration

- Calibration achieves significant reduction of FWHM close to single pixel FWHM
- Tail to lower ToT is present
→ Charge sharing



Quality Control of Calibration

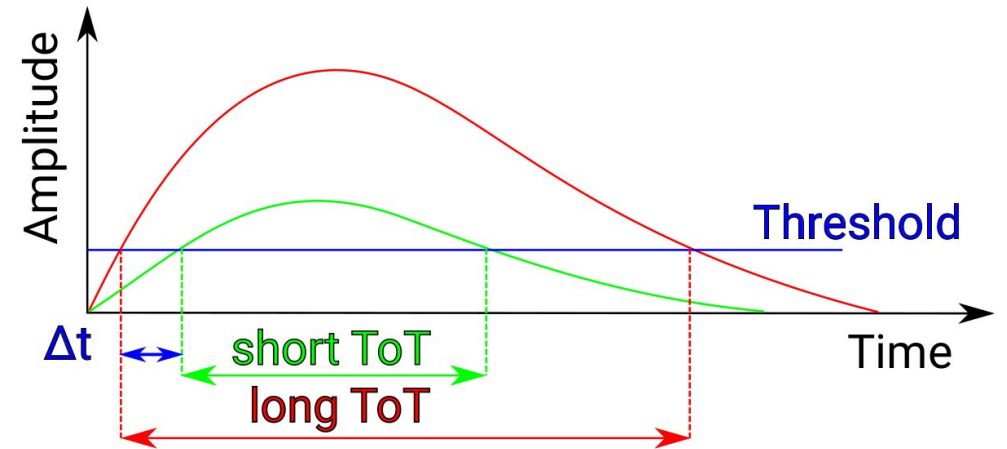
- Correlation between FWHM/Median before and after calibration
- Calibration achieves more uniform Fe55 response



Measurement Setup

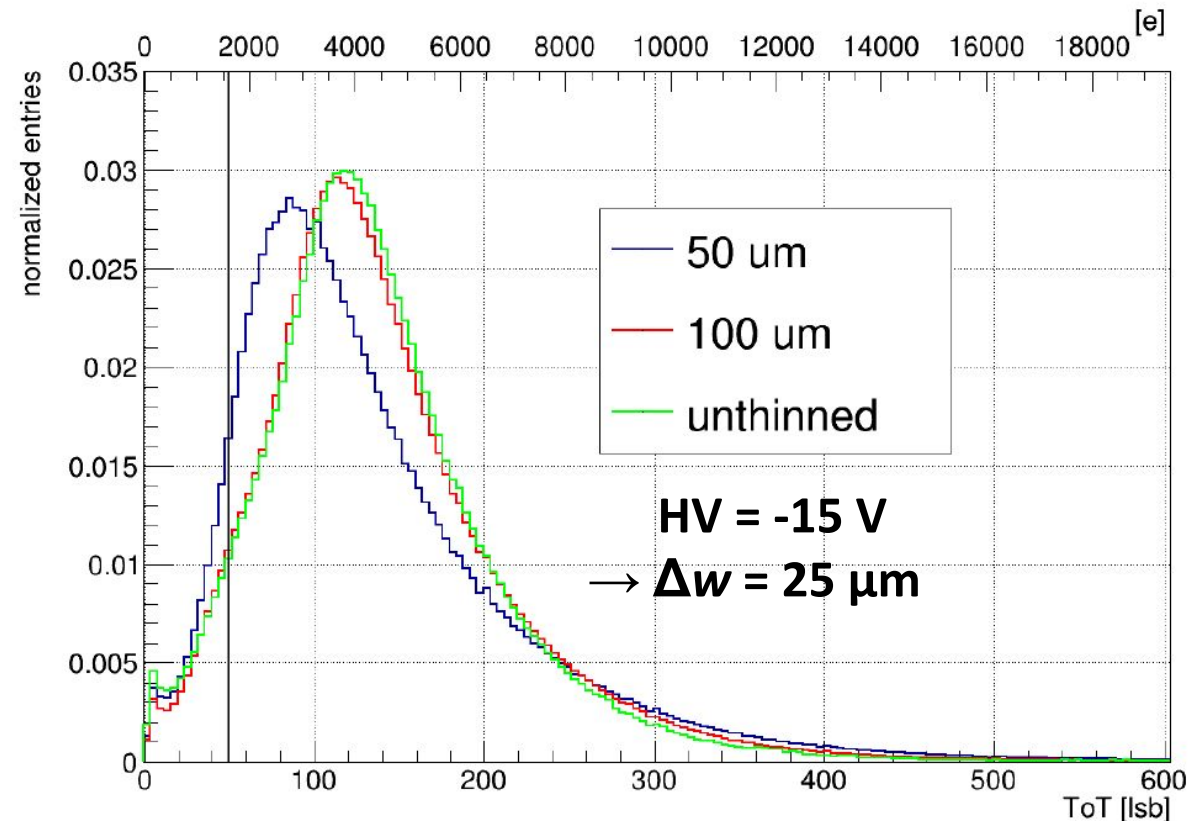
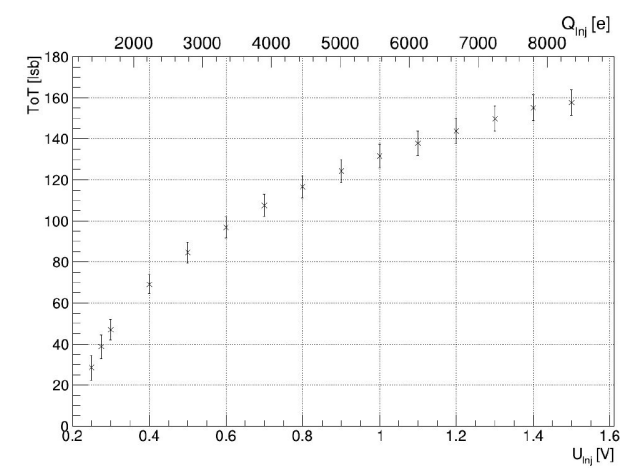
- Study charge collection by varying HV with various signal sources
- Compare **ToT** & Cluster size of DUTs at **same configuration & HV**
- ^{90}Sr : 2.28 MeV e^- source \rightarrow continuous spectrum
- ^{55}Fe : Monochromatic x-ray source 5.9 keV
- Testbeam@DESY: 4 GeV electrons

\rightarrow Following results focus on:
 $d=50\ \mu\text{m}, 100\ \mu\text{m}, 600\ \mu\text{m}$ $\rho = 370\ \Omega\text{cm}$



Calibrated ToT studies Sr90

- Sr90: β^- decay \rightarrow continuous spectrum up to 2.28 MeV
 \rightarrow MPV ~ 0.8 MeV $\rightarrow \sim 2600$ e $^-$ from drift
- Both thicker sensors have larger ToT
 \rightarrow significantly more charge collection



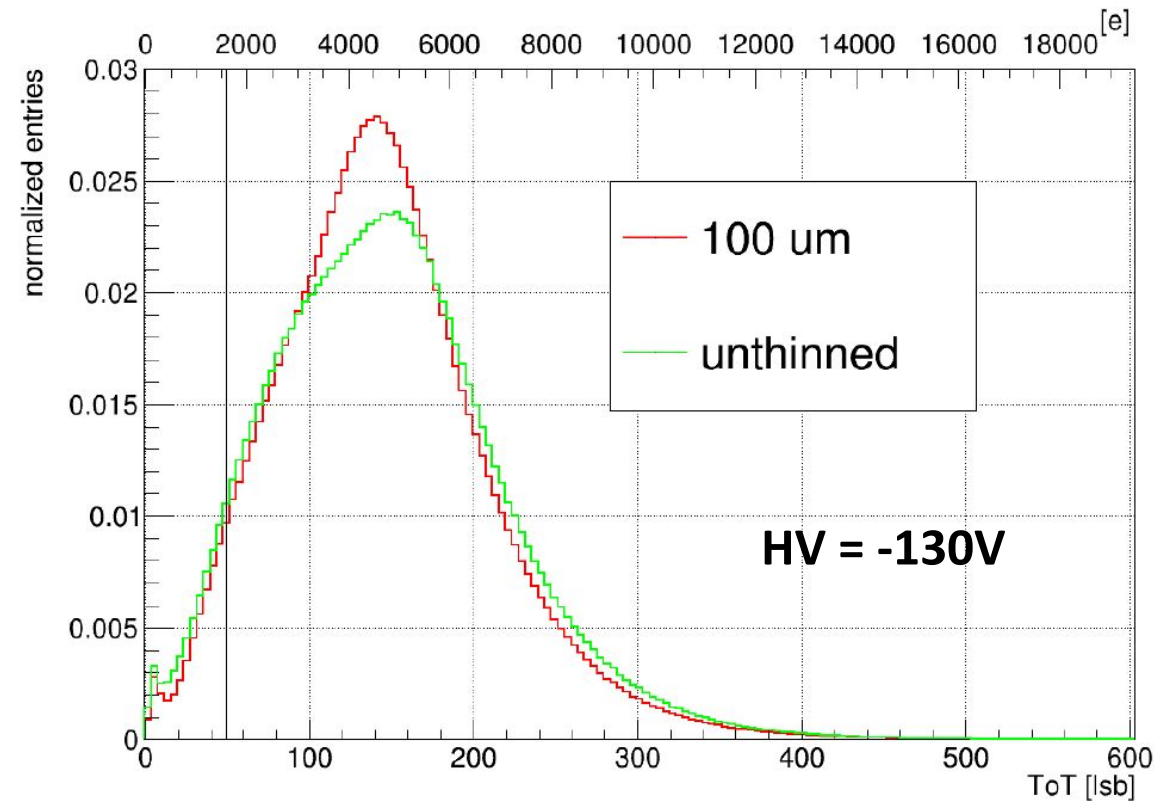
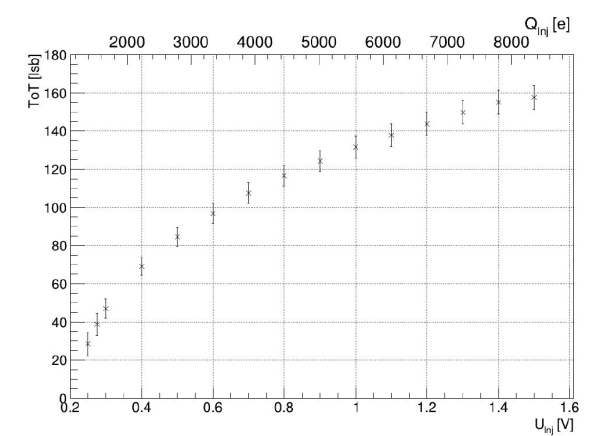
only estimated!



Chip Thickness	e $^-$ from drift	e $^-$ (^{55}Fe Calibration)	e $^-$ (Injection Gauging)
50 μm	2600	2750	2750
100 μm	2600	3650	4300
unthinned	2600	3750	4450

Calibrated ToT studies Sr90

- Large shoulder for unthinned sensor
- Huge amount of charge collected
→ Linear Calibration not applicable
- Injection Calibration problematic as well
→ Higher energetic x-ray sources needed



Preliminary!



Chip Thickness	e ⁻ from drift	e ⁻ (⁵⁵ Fe Calibration)	e ⁻ (Injection Gauging)
100 μm	6700	3900	6400
unthinned	6700	4800	-